



LIGITEK

LIGITEK ELECTRONICS CO.,LTD.
Property of Ligitek Only

ROUND TYPE LED LAMPS



Lead-Free Parts

LG3330-PF

DATA SHEET

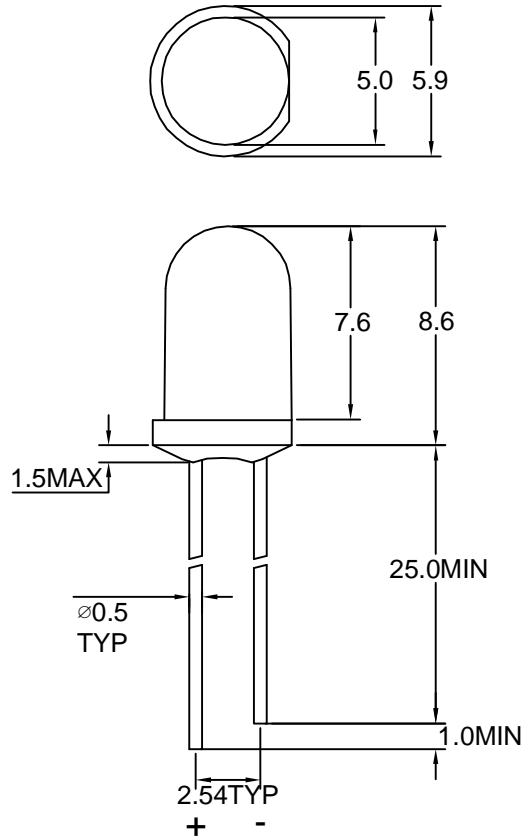
DOC. NO : QW0905-LG3330-PF-08

REV. : A

DATE : 28 - Oct - 2008

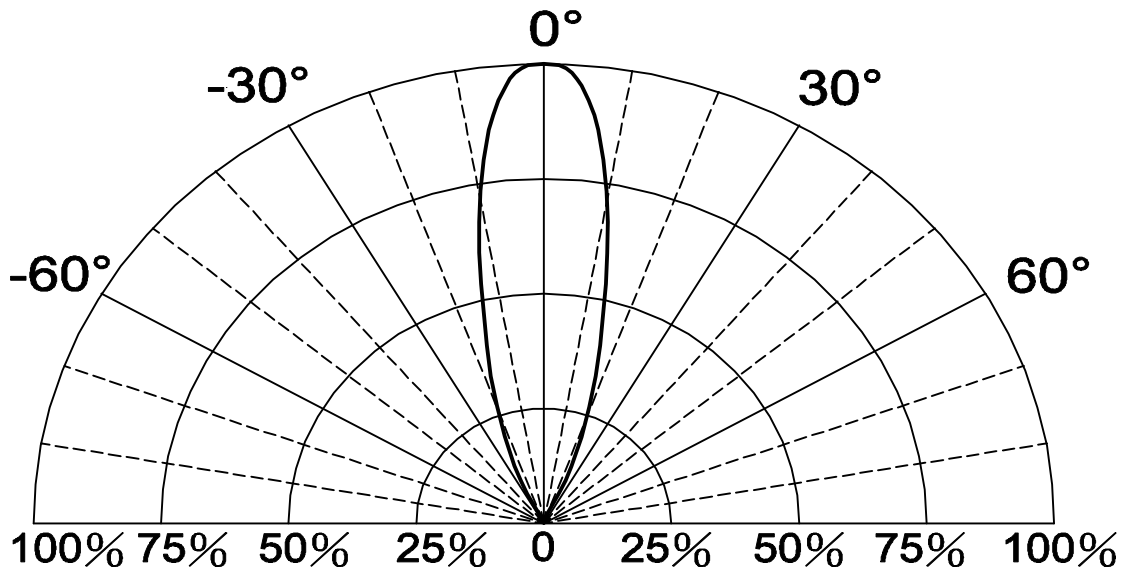


Package Dimensions



Note : 1.All dimension are in millimeter tolerance is $\pm 0.25\text{mm}$ unless otherwise noted.
2.Specifications are subject to change without notice.

Directivity Radiation





Absolute Maximum Ratings at Ta=25 °C

| Parameter | Symbol | Ratings | UNIT |
|---|--------|------------|------|
| | | Green | |
| Forward Current | IF | 15 | mA |
| Peak Forward Current Duty 1/10@10KHz | IFP | 80 | mA |
| Power Dissipation | PD | 50 | mW |
| Reverse Current @5V | Ir | 10 | μA |
| Operating Temperature | Topr | -40 ~ +85 | °C |
| Storage Temperature | Tstg | -40 ~ +100 | °C |

Typical Electrical & Optical Characteristics (Ta=25 °C)

| PART NO | MATERIAL | COLOR | | Peak wave length λ P nm | Spectral halfwidth Δ λ nm | Forward voltage @10mA(V) | | Luminous intensity @10mA(mcd) | | Viewing angle 2θ 1/2 (deg) |
|-----------|----------|---------|----------------|----------------------------|------------------------------|-----------------------------|------|----------------------------------|------|----------------------------------|
| | | Emitted | Lens | | | Min. | Typ. | Min. | Typ. | |
| LG3330-PF | GaP | Green | Green Diffused | 565 | 30 | 1.7 | 2.1 | 12 | 20 | 28 |

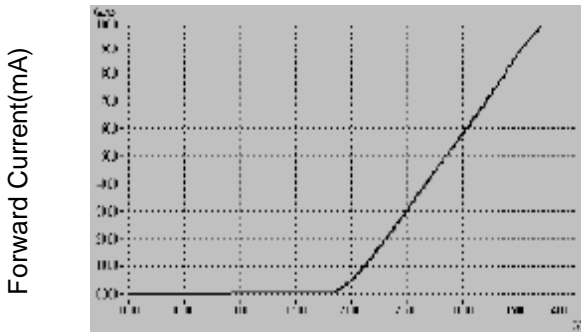
Note : 1.The forward voltage data did not including ±0.1V testing tolerance.
 2. The luminous intensity data did not including ±15% testing tolerance.



Typical Electro-Optical Characteristics Curve

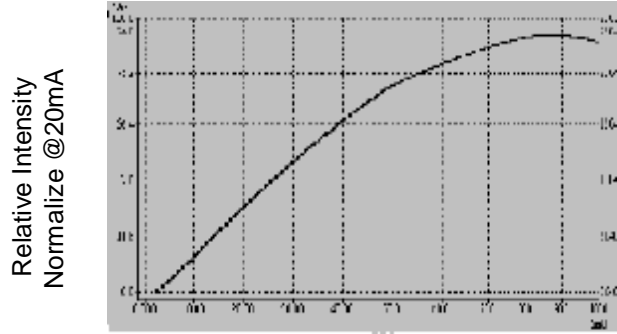
G CHIP

Fig.1 Forward current vs. Forward Voltage



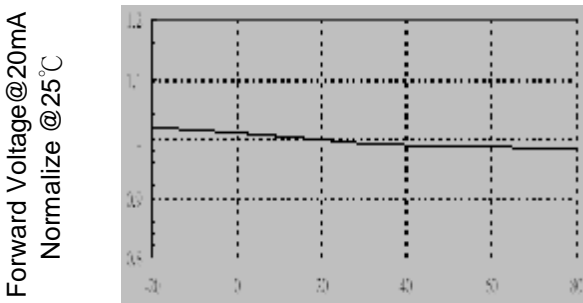
Forward Voltage(V)

Fig.2 Relative Intensity vs. Forward Current



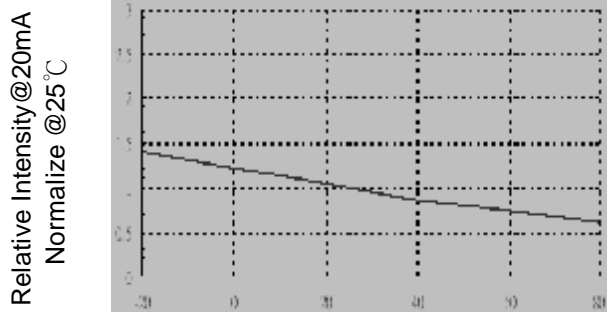
Forward Current(mA)

Fig.3 Forward Voltage vs. Temperature



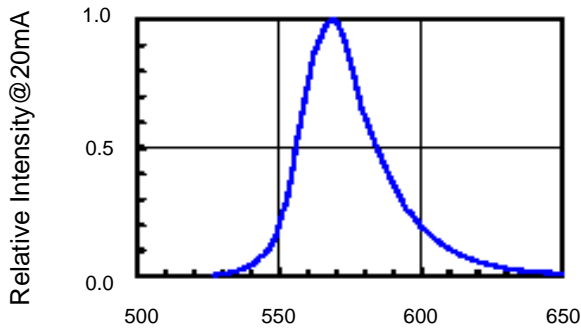
Ambient Temperature(°C)

Fig.4 Relative Intensity vs. Temperature



Ambient Temperature(°C)

Fig.5 Relative Intensity vs. Wavelength



Wavelength (nm)

Fig.6 Directive Radiation



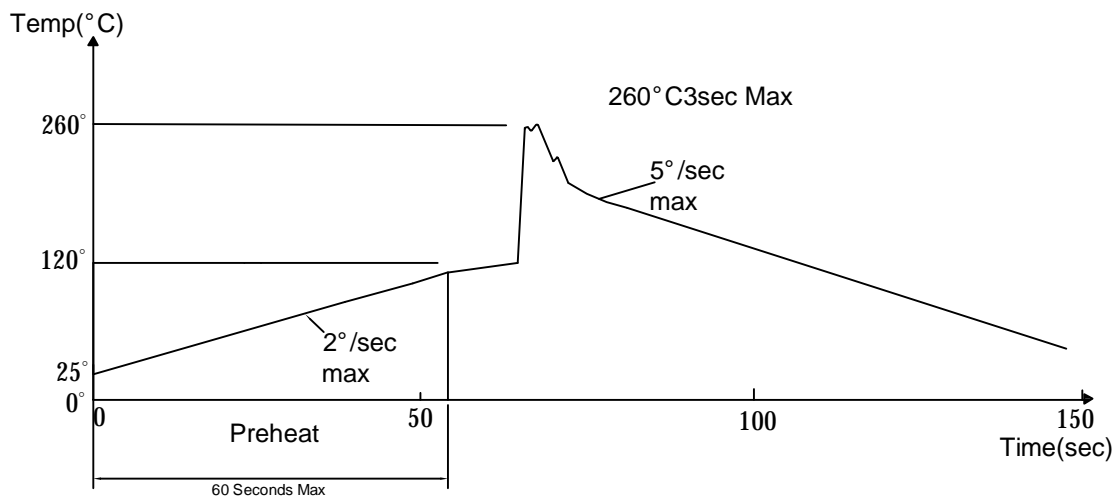
Soldering Condition(Pb-Free)

1.Iron:

Soldering Iron:30W Max
Temperature 350 ° C Max
Soldering Time:3 Seconds Max(One time only)
Distance:2mm Min(From solder joint to body)

2.Wave Soldering Profile

Dip Soldering
Preheat: 120° C Max
Preheat time: 60seconds Max
Ramp-up
2° C/sec(max)
Ramp-Down:-5° C/sec(max)
Solder Bath:260° C Max
Dipping Time:3 seconds Max
Distance:2mm Min(From solder joint to body)



Note: 1.Wave solder should not be made more than one time.
2.You can just only select one of the soldering conditions as above.

**Reliability Test:**

| Test Item | Test Condition | Description | Reference Standard |
|-------------------------------------|--|---|--|
| Operating Life Test | 1.Under Room Temperature 2.If=20mA 3.t=1000 hrs (-24hrs, +72hrs) | This test is conducted for the purpose of determining the resistance of a part in electrical and thermal stressed. | MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1 |
| High Temperature Storage Test | 1.Ta=105 °C ±5°C 2.t=1000 hrs (-24hrs, +72hrs) | The purpose of this is the resistance of the device which is laid under condition of high temperature for hours. | MIL-STD-883:1008 JIS C 7021: B-10 |
| Low Temperature Storage Test | 1.Ta=-40 °C ±5°C 2.t=1000 hrs (-24hrs, +72hrs) | The purpose of this is the resistance of the device which is laid under condition of low temperature for hours. | JIS C 7021: B-12 |
| High Temperature High Humidity Test | 1.Ta=65 °C ±5°C 2.RH=90 %~95% 3.t=240hrs ±2hrs | The purpose of this test is the resistance of the device under tropical for hours. | MIL-STD-202:103B JIS C 7021: B-11 |
| Thermal Shock Test | 1.Ta=105 °C ±5°C & -40°C ±5°C (10min) (10min) 2.total 10 cycles | The purpose of this is the resistance of the device to sudden extreme changes in high and low temperature. | MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011 |
| Solder Resistance Test | 1.T.Sol=260 °C ±5°C 2.Dwell time= 10 ±1sec. | This test intended to determine the thermal characteristic resistance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire. | MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1 |
| Solderability Test | 1.T.Sol=230 °C ±5°C 2.Dwell time=5 ±1sec | This test intended to see soldering well performed or not. | MIL-STD-202: 208D MIL-STD-750: 2026 MIL-STD-883: 2003 JIS C 7021: A-2 |